nexperia

Reliability Monitoring Results

Quarters: Q1/2021 to Q4/2021

Based on structural similarity

Suppli	ier	User Part Number							
Nexperia B.V.		74HCT112D	74HCT112D						
Part D	escription: Dual J-K flip-flo	p with set and reset; negat	ive-edge trigger;	; TTL enabled					
Pro	nction Family: HC(T) cess family: Super micron ckage family: SO								
JESD4	7 Test	Test Conditions	Duration	# Lots	# Quantity	# Rejects			
# 1	TEST Pre- and Post-Stress	Tamb = 25 °C	N/A	see below	all parts	see			
# 1	Electrical Test		N/A	See Delow	all parts	below			
# 2	PC Preconditioning	JESD22-A113 MSL 1	N/A	378	26431	0			
	HTOL EFR	JESD22-A108	48 hours						
# 5a	High Temperature	$Tj = 150^{\circ}C$	or	58	23674	0			
	Operating Life Extrinsic HTOL IFR	$V_{CCMAX} \le V \le 1.2^*V_{CCMAX}$ JESD22-A108	168 hours						
# 5b	High Temperature Operating Life Intrinsic	Tj = 150° C VCCMAX $\leq V \leq 1.2^{*}$ VCCMAX	≥500 hours	55	2997	0			
# 7	TC Temperature Cycling	JESD22-A104 -65 °C to 150°C	≥500 cycles	49	15770	4			
# 9	uHAST / HAST unbiased or biased High Accelerated Stress Test	JESD22-A101 Tamb = 130 °C, RH = 85%, V = V _{CCMAX}	96 hours	187	10661	0			

Calculation of PPM, FIT and MTTF

Test considered for PPM calculation: High Temperature Operating LifeTest Extrinsic (HTOL EFR, Test # 5a above) Test considered for FIT and MTTF calculations: High Temperature Operating LifeTest Intrinsic(HTOL IFR, Test # 5b above)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Product Family	Package Family	Quantity	Rejects	Extrinsic Failure Rate (PPM)	Intrinsic Failure Rate (FIT)	MTTF (hrs)
HC(T)	SO	2997	0	39	1.3	8.12 E+08

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